



Contribution ID: 249

Type: **SIG Forum**

Critical Thinking SIG forum: JALT Critical Thinking SIG Forum

Sunday 18 May 2025 12:30 (1 hour)

TITLE

RELEVANT SIG

Critical Thinking

FORMAT

Short English description

KEYWORDS

First-time presenter?

ABSTRACT

The JALT Critical Thinking SIG Forum will feature presentations that promote the use and development of critical thinking in language courses. Among the topics to be presented by the speakers are learning ethics through analyzing media content, enhancing critical thinking through debate, ensuring student authorship through AI-generated tests, and examining the role of critical thinking skills in lecture comprehension. Additionally, future opportunities for participating, presenting, and publishing with the CT SIG will be presented.

Presenters: GANN, David; DEVITTE, David Wayne; Mr DUNN, James (Meiji University); JENNINGS, Stephen; HOOPER, Todd (Setsunan University); WANG, Xiaodan

Session Classification: B3-202 Forum (60) SAT: JALT CALL SIG Forum; ICLE SIG Forum; Pragmatics SIG Forum; MAVR SIG Forum; SUN: SPIN Forum; CT SIG Forum, TYL SIG Forum